

Ultraspec-III

laser illuminator



Multi-line laser illuminator for semiconductor backside analysis

Product Highlights

- ◆ Vastly improved imaging over conventional methods
- ◆ Three laser lines can be used independently or blended
 - ◆ Suits most available backside microscopes
- ◆ Assists and optimizes emission microscopy, FIB, voltage, thermal, Moiré, SIFT, and most other backside techniques

Unmatched Backside Imaging

Our patented ULTRASPEC-III coherent laser illumination source is designed to meet the needs of today's photoemission microscopes as well as most backside imaging stations.

In standard configuration with laser wavelengths at **670nm**, **1064nm** and **1300nm**, you have the immediate flexibility to illuminate just the topside or silicon surface and then switch to 1064nm (or 1300nm if you have a longer wavelength sensitive camera) for crisp high contrast backside imaging. Produces superior backside images through the silicon with phase-blended laser illumination.

You wouldn't limit your microscope with improper optics, so why limit it with improper illumination?

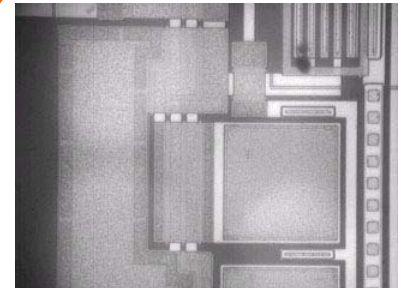
Note how the monochromatic source brings out diffraction-limited details in the backside image (lower image, opposite). The system gives no chromatic aberration and is compatible with many oil immersion objectives.

ULTRASPEC-III is produced under license by ULTRA TEC Manufacturing, Inc. and is protected by the following US Patents: #6112004 & #6134365.

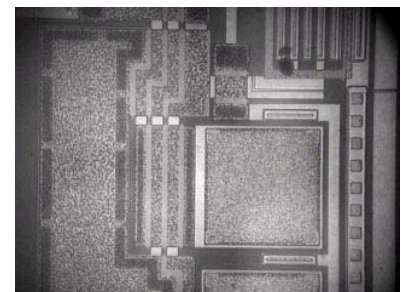


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See what you have been missing!



Backside image produced with standard bulb illuminator



Same area of part illuminated with ULTRASPEC-III

